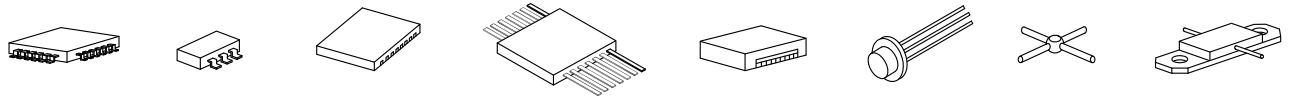


RF Device Test Head GURF series

- Measurable signal is DC~10GHz
- JC Electronics high reliable probe pin
- Because of SMA output, it is easy to connect to testing equipment.
- Economical by using standard parts
- We accept custom requests. Minimum order quantity is one.

Target device

DBM, RF AMP, PLL, VCO, RF etc.



Specifications (example) :

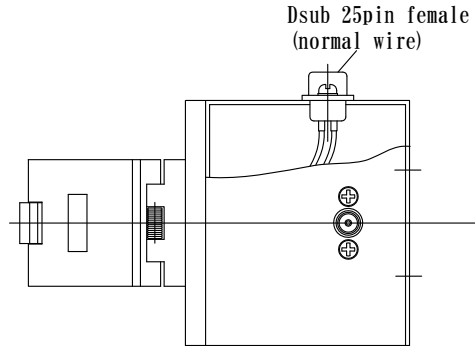
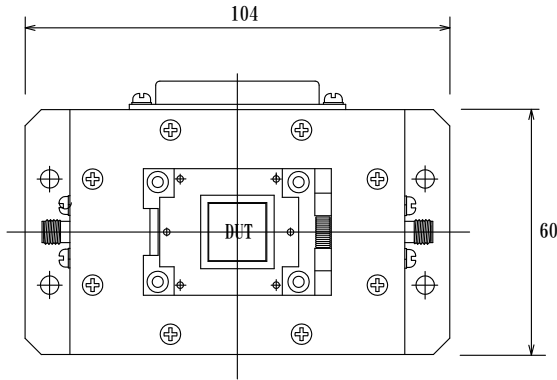
Frequency Range	: DC~18GHz	
RF Return Loss (at 50Ω)	: DC~10GHz	10.0dB
RF Insertion Loss (at 50Ω)	: DC~10GHz	1.0dB
Duability	: more than 5000	

Materials (example) :

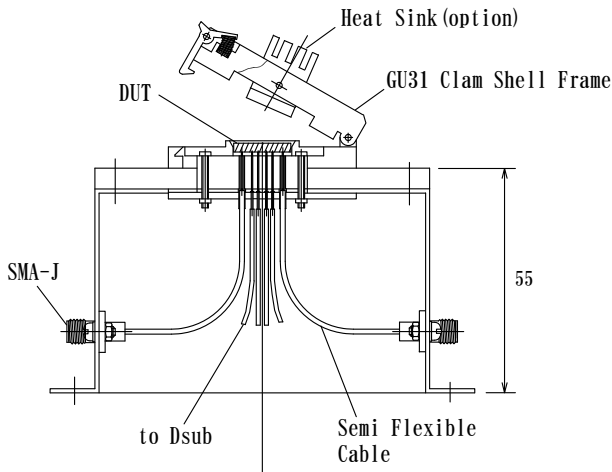
Probe Pin	
Plunger	: Beryllium copper, Ni over Gold plated
Barrel	: Brass, Ni over Gold plated
Spring	: Music wire, Ni over Gold plated
Insulator	: Teflon
Case Body	: Brass, Ni plated
Gu31 Frame	: PPS UL94V-0

RF Device Test Head GURF series example

Example of RF 2 circuits and 8 normal wires

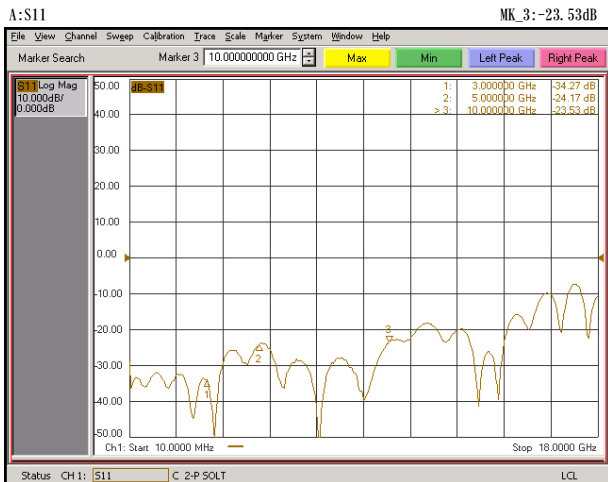


Maximum number of wires is decided by device pitch, number of RF circuits and number of normal wires.



<< Reference Data >>

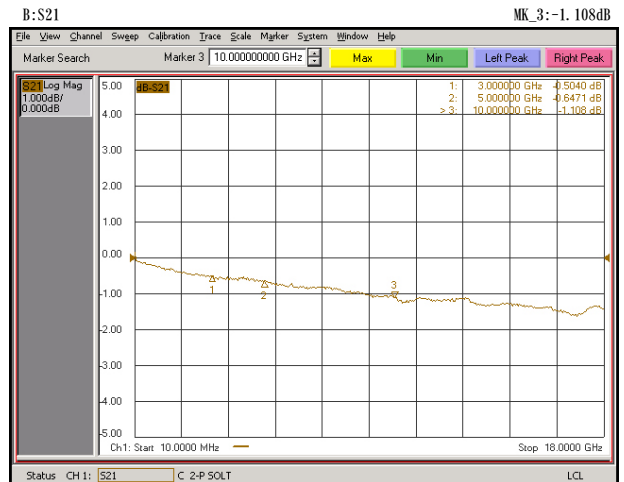
Return Loss



A: START:10MHz

A: STOP:18.0GHz

Insertion Loss



B: START:10MHz

B: STOP:18.0GHz